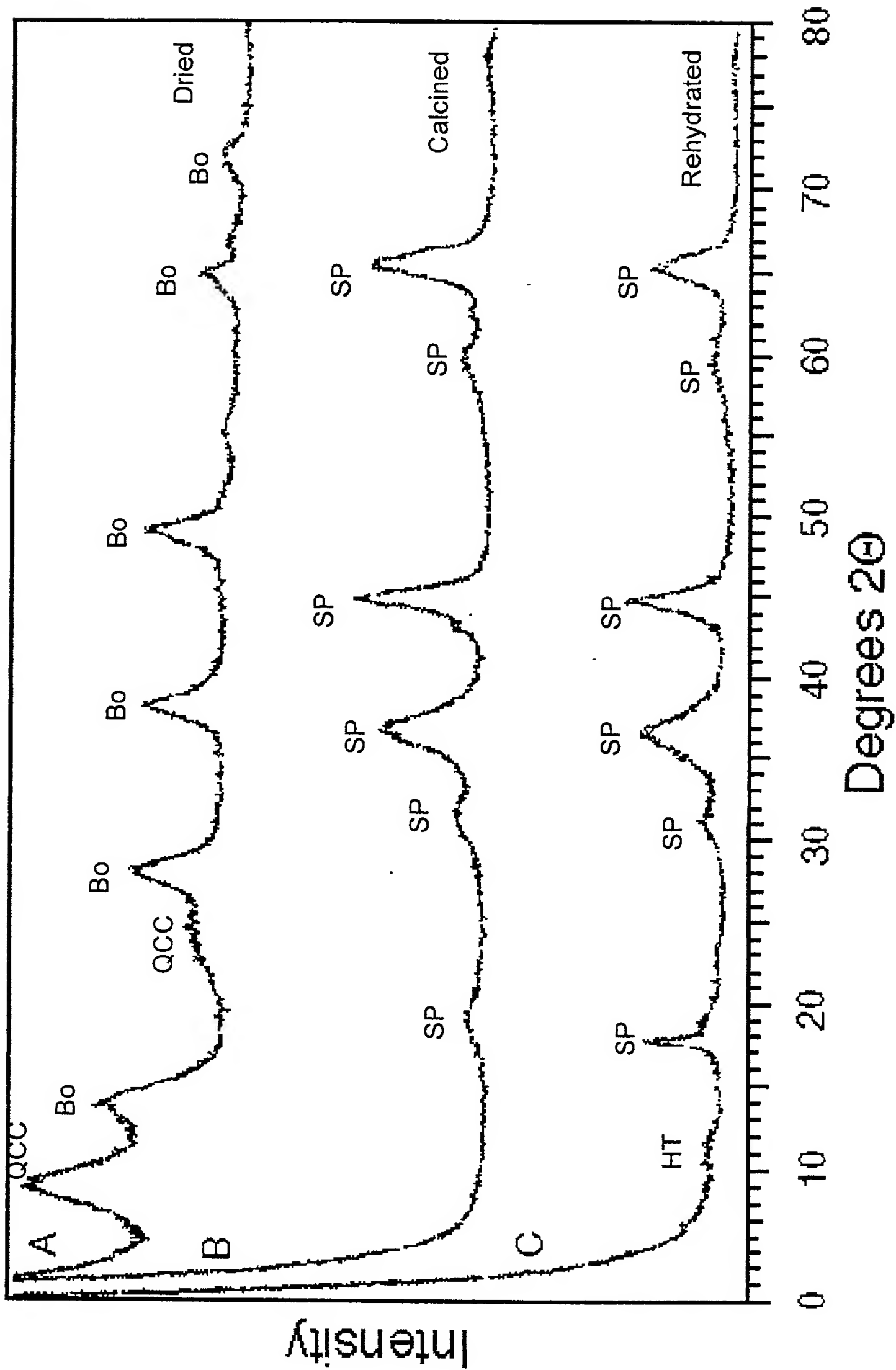


Small-angle X-ray diffraction patterns of the samples were recorded on a Siemens Kristalloflex D5000 X-ray diffractometer using Cu K α radiation (40 kV, 15 mA) at a scanning rate of 2 $^\circ$ /min. The diffraction patterns were recorded in the 2 θ range of 5–80 $^\circ$. The data were collected and analyzed using the X'Pert HighScore Plus software.

Figure 1



Small-angle X-ray diffraction patterns of the samples. The x-axis represents the diffraction angle 2θ in degrees, and the y-axis represents the intensity in arbitrary units. The patterns show the evolution of the diffraction peaks during the synthesis and treatment of the samples.

Figure 3

